

Contents

Abbreviations	ix
Preface	xi
1. History	1
2. Principles	5
What are X-rays?	5
Characteristic X-rays	5
Bremsstrahlung	7
Ionization cross-section	10
Fluorescence yield	12
X-ray absorption	13
Insulators, conductors and semiconductors	15
3. The energy-dispersive X-ray detector	19
Introduction	19
The semiconductor X-ray detector	19
Principles of operation	19
Structure of the detector	20
Cooling the detector	20
Detector windows	21
Collimation of the detector	23
Protection against spurious electron bombardment	23
General mechanical details	25
The X-ray analyser	27
The FET and detector reset	28
The pulse processor	28
Multi-channel analyser	30
Details of the spectrum	31
Characteristic peaks	32
Spurious responses in the system	36
Detector icing	40

New detector technologies	42
Silicon drift detector	42
Microcalorimeter	43
4. Spectral processing	45
Introduction	45
Background stripping	45
Window integrals	45
Polynomial curve fitting	46
Top-hat filtering	47
Background modelling	48
Deconvolution of overlapping peaks	49
Statistical considerations	53
Poisson statistics	53
Gaussian statistics	54
The impact of statistics	54
The effect of the background	55
Analytical strategy	56
5. Energy-dispersive X-ray microanalysis in the scanning electron microscope	59
Introduction	59
Fundamentals of X-ray analysis in the SEM	63
Quantitative microanalysis in the SEM	68
ZAF correction	68
Standardless ZAF correction	70
Other correction methods	71
Semi-quantitative microanalysis in the SEM	72
Discussion	72
Fingerprinting	75
Examples	75
Conditions for X-ray microanalysis in the SEM	77
EDX analysis in the VP-SEM and ESEM	78
Inhomogeneous samples	81
Concluding remarks	83
6. X-ray microanalysis in the transmission electron microscope	85
Introduction	85
Principles of quantitative analysis in the TEM	86
Cliff-Lorimer method	86
Hall method	89
Absorption, fluorescence and other sources of error	91
Self-absorption of X-rays in the sample	91
Fluorescence	94

Excitation by electrons	96
Excitation by stray X-rays	97
Precision of quantitative analysis	98
Spatial resolution	100
Introduction	100
Spatial resolution in thin foils	101
Analysis of particles	104
Analysis of interfaces	107
Microscope considerations	109
7. X-ray mapping	113
Introduction	113
Hardware implementation	113
Statistical considerations	115
Examples	117
Spectral overlaps	118
Other applications	118
Spectral imaging	120
Quantitative X-ray mapping	121
Concluding comments	123
8. Energy-dispersive X-ray analysis compared with other techniques	125
Introduction	125
Wavelength-dispersive X-ray analysis – electron probe microanalysis (EPMA)	125
Spectral resolution	127
Peak to background	127
Spectral acquisition	128
Dead time and counting rate	128
Geometrical considerations	128
Electron energy-loss spectroscopy (EELS)	128
Auger electron spectroscopy (AES)	130
X-ray photoelectron spectroscopy (XPS)	130
X-ray fluorescence (XRF)	131
Atom probe	133
Overall strengths and weaknesses	133
Bibliography	135
Index	139